

<b>Notice of References Cited</b>	Application/Control No. 09/586,601	Applicant(s)/Patent Under Reexamination ONO, SHUJI	
	Examiner Nhan T. Tran	Art Unit 2615	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,850,470	12-1998	Kung et al.	382/118
*	B	US-6,823,080	11-2004	Iijima et al.	382/154
*	C	US-5,878,156	03-1999	Okumura, Tomoko	382/118
*	D	US-6,606,117	08-2003	Windle, John Richard	348/239
*	E	US-2003/0193610	10-2003	NOZAKI et al.	348/345
*	F	US-2002/0085747	07-2002	YOSHIGAHARA et al.	382/154
*	G	US-6,262,778	07-2001	Nonweiler et al.	348/586
*	H	US-6,226,396	05-2001	Marugame, Atsushi	382/154
*	I	US-6,504,944	01-2003	Mihara et al.	382/118
*	J	US-5,905,807	05-1999	Kado et al.	382/118
*	K	US-6,184,926	02-2001	Khosravi et al.	348/239
*	L	US-6,940,545	09-2005	Ray et al.	348/222.1
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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